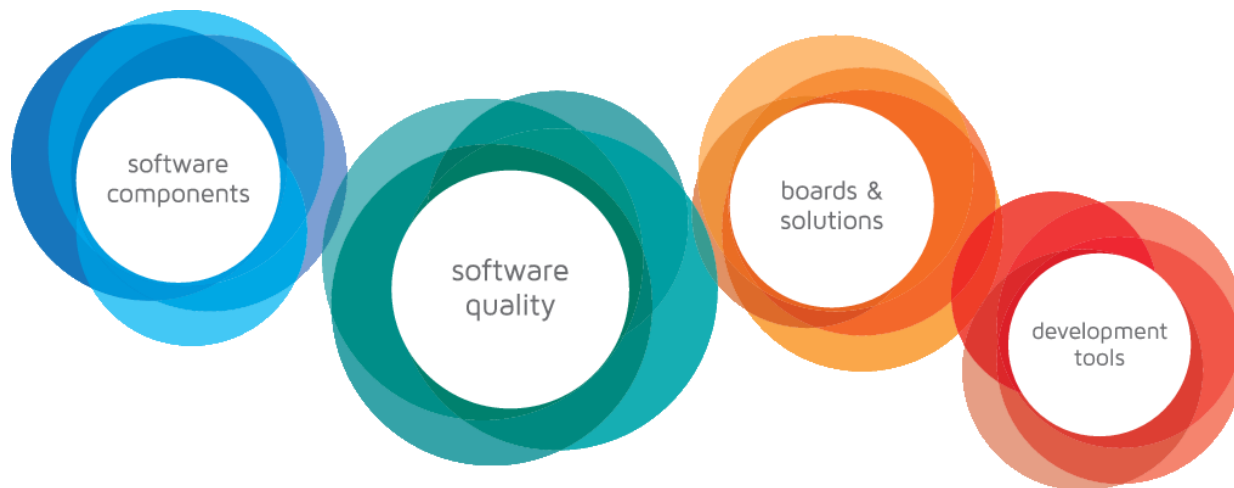


# Snel en veilig hardware testen



**Logic Technology**

# SOLUTIONS

## Software Components



*Logic Technology offers a variety of tested software components that make sure your design meets the industry standards and assure compatibility now and in the future.*



## Software Quality



*Logic Technology helps you to be more productive and seamlessly improve the quality of your software.*



# SOLUTIONS

## Boards & Solutions



*Logic replaces the complexity of the hardware design and helps to improve overall board testability by offering a wide range of standard and custom made modules and supplies.*



## Development Tools



*Logic Technology keeps you agile with high performance, feature rich, development tools and debuggers, tuned for various microcontroller and processor architectures.*



- What ?
- Why ?
- at any Cost ?
- How ?
- Challenge ?
- Solution ?

# What Test

- Smoke Test
- PCB Inspection
- ICT / FP
- Prototype Test/Debug
- JTAG
- **Functional Testing**

# What Test ?

- From Wikipedia, the free encyclopedia
- **Automatic** or **automated test equipment (ATE)** is any apparatus that performs tests on a device, known as the [Device Under Test](#) (DUT), Equipment Under Test (EUT) or Unit Under Test (UUT), using [automation](#) to quickly perform measurements and evaluate the test results.



- What?
- **Why?**
- at any Cost ?
- How ?
- Challenge ?
- Solution ?



# Why Test?

- Customers
- Short Term vss. Long Term Costs



- If you don't have time to do it right, when will you have time to do it over?  
( John Wooden )

# Skip Functional Test ?

- Seems a silly question but considerable companies still only box test or only conduct basic tests on raw electronic assemblies.
  - Basic tests can be just visual inspection
- Test equipment is often deemed too expensive and requires too much resources to implement.
  - Especially if the volume is low
  - Labour cost are increasing

# Skip Functional Test ?

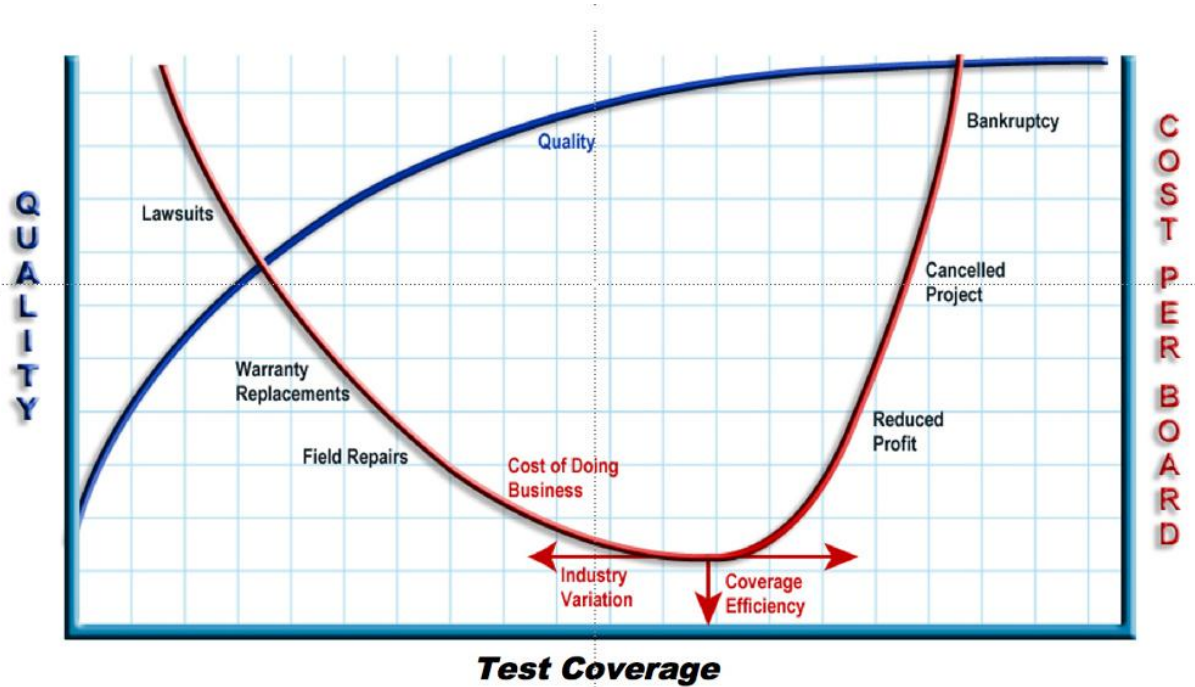
- Most 'Test' Engineers in smaller / medium size organisations do not have the required skills to develop complex test equipment.
  - Companies cannot afford to employ full blown electronic engineers
  - As hardware get more complex so does the testing requirements
- Obviously the answer is 'NO' but the pressure on reducing budgets normally means that 'Functional Testing' is given a significantly lower priority

- What?
- Why?
- **at any Cost ?**
- How ?
- Challenge ?
- Solution ?

# Test at any Cost ?

- The metric of development and **test efficiency** is typically a formula that includes the following factors:
  1. Cost
  2. Duration
  3. Safety
  4. Feasibility

# At Any Cost ?



- What?
- Why?
- at any Cost ?
- **How ?**
- Challenge ?
- Solution ?

# How ?

Write a Testplan

- IMPOSSIBLE only means you haven't found the Solution yet



# How ?

A test plan documents the **strategy** that will be used to verify and ensure that a product or system meets its design specifications and other requirements.

- A test plan is usually prepared by or with significant input from Test Engineers

- Methods
  - test methods may be determined by standards, regulatory agencies, or contractual agreement
  - test equipment to be used in the performance of the tests and establish pass/fail criteria
- Responsibilities
  - test methods at each stage of the product life
  - plan, acquire or develop test equipment and other resources necessary to implement the test methods

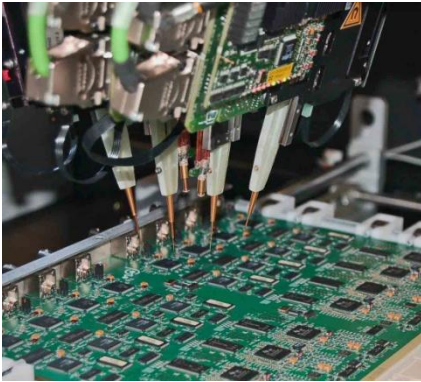
# How ?

One outcome of a successful test plan should be a record or report of the verification of all design specifications and requirements as agreed upon by all parties



- add **certain** testability features to a hardware product design

# How To Connect ?

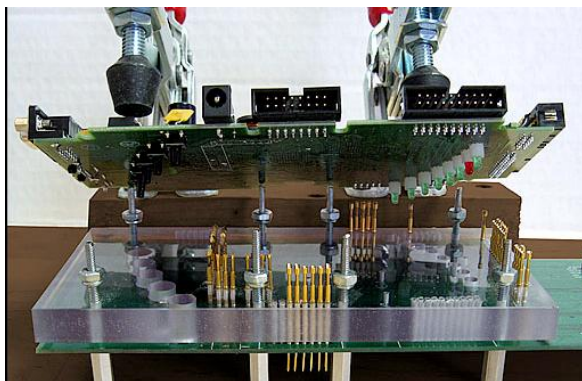


From Wikipedia, the free encyclopedia

**Mass interconnect** systems act as the connector interface between test instruments ([PXI](#), [VXI](#), [LXI](#), GPIB, SCXI, & PCI) and devices/units under test (D/UUT).

Used in [defense](#), [aerospace](#), automotive, [manufacturing](#), and other applications. By mating a receiver on the tester side with an **interchangeable test adapter** (ITA) on the UUT, the mass interconnect enables the entire system to mate together at one time. Mass InterConnect systems are available in multiple sizes and configurations to accommodate virtually any testing requirement.

Companies that manufacture mass interconnects include: Virginia Panel Corporation, Mac Panel, & Everett Charles Technologies.



**Cable Assemblies and Receiver Patchcords:** Modules connect to the instrument-specific connector(s) and are also available in PCB adapter configurations that accept COTS (commercial off-the-shelf) cable assemblies. Receiver patchcords allow discrete wiring.

**Receiver Modules:** Present multiple configurations of signal, power, RF/coaxial, pneumatic, vacuum, thermocouple, or fiber optic in varying densities.

**Interchangeable Test Adapter (ITA):** Mates to the Receiver and houses the modules, PCB adapters, cable assemblies, and patchcords for connection to the UUT.

**ITA Modules:** Connect to the Receiver modules in the corresponding configurations and is the final connection before engaging the test instrument to the UUT.

D/UUT >



**ITA Enclosures:** Protect and provide strain relief for wiring. Enclosures offer a mounting surface for UUT accessories such as edge-card adapters and other connectors.

**ITA Patchcords:** Supply the user a contact with pre-terminated wire in a single or double-ended format to connect the ITA to the UUT in a customized arrangement.



**Receiver:** A rugged InterConnect mechanism to house connector modules, patchcords, cable assemblies, and PCB adapters for connection to test instrumentation. Mates with the ITA frame.

## Good

- Small
- Modular
- Wide variety of modules
- Rapid Test development
- Reduce Overall Cost



## Reality

- Big
- Expensive Capital invest
- Require adaptation ( Fixtures ) for each UUT.
- Costs on HW and SW Program development.



What Test ?

Why Test ?

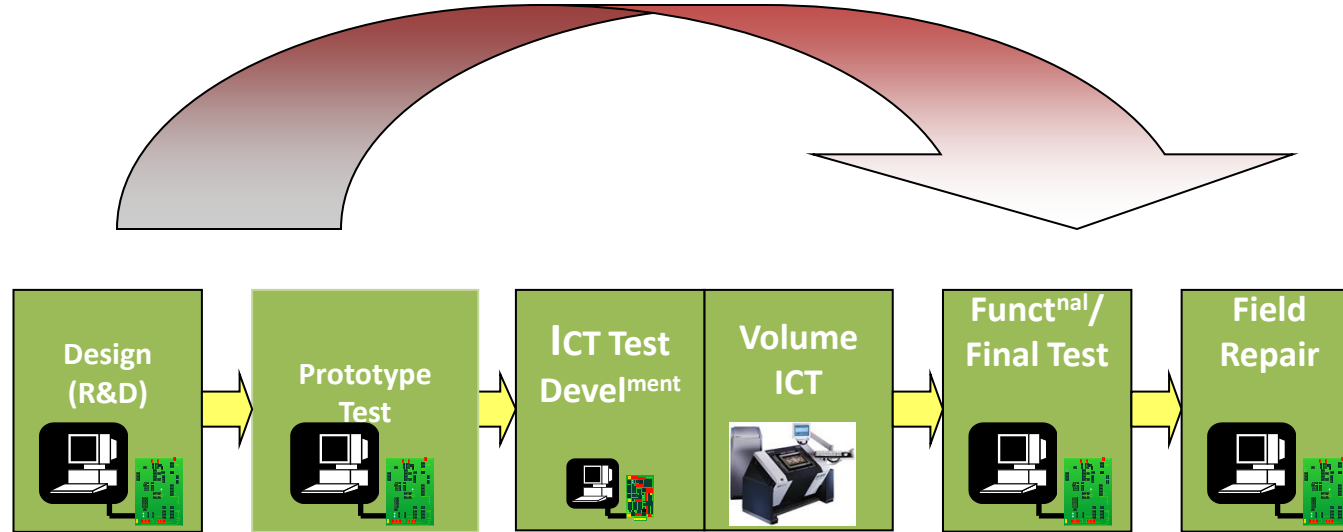
Test at any Cost ?

How to Test ?

**Challenge ?**

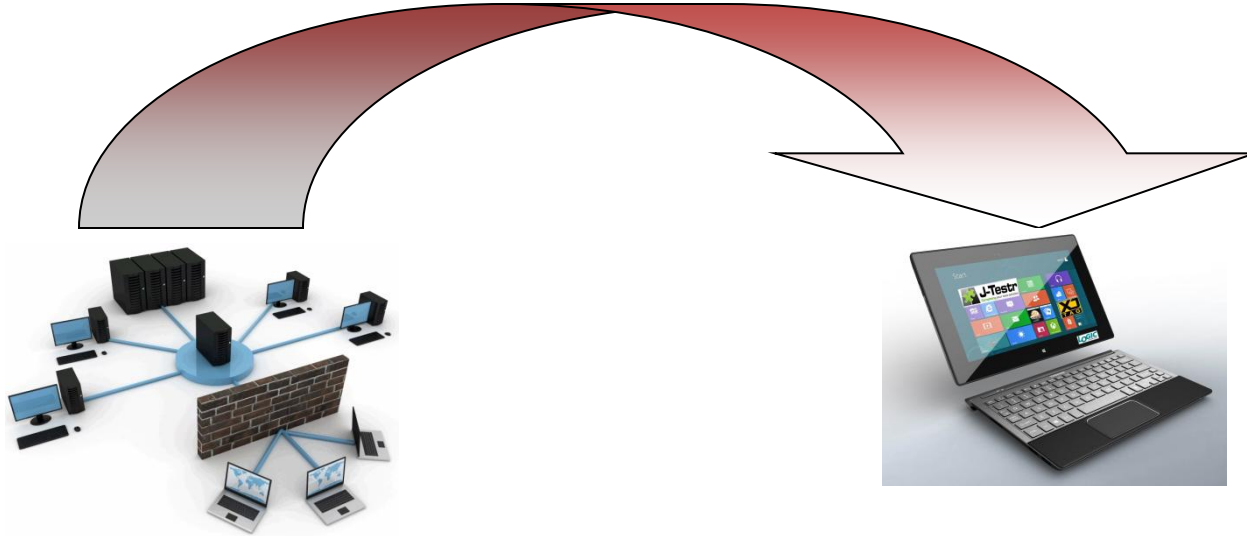
Solution ?

# Challenge



**Create a highly integrated Test concept in terms of being portable throughout the lifecycle**

# Challenge



**Remove software Overhead to simplify the development  
and reduce deployment costs**

What Test ?

Why Test ?

Test at any Cost ?

How to Test ?

Challenge ?

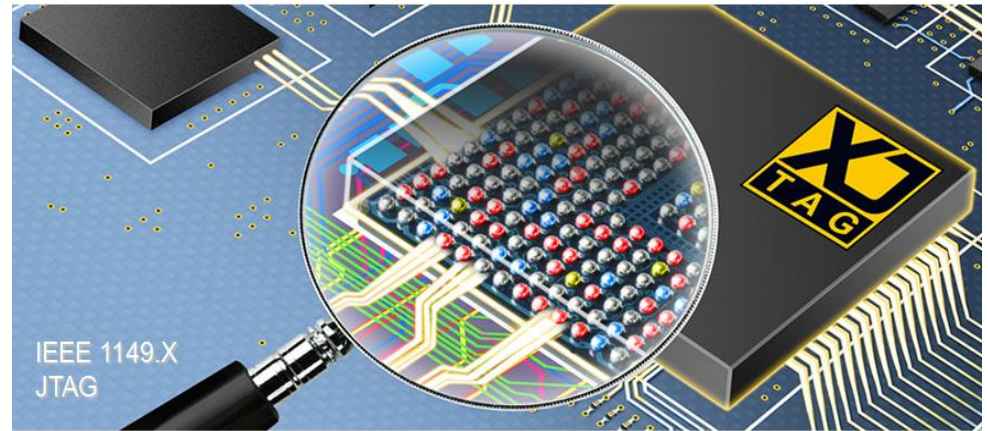
**Solution ?**

# JTAG compatible Functional Tester

## JTAG

### Boundary Scan IEEE 1149.1

- Std= interface description
- vendor lock you in
- SW development requires expertise
- Digital only
  - Test Extensions ( I/O modules )
- Manufacturing Test
- Program Devices
- Still Requires FUNCTIONAL TEST



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TECHNOLOGY  
*There's always a Logic Solution!*





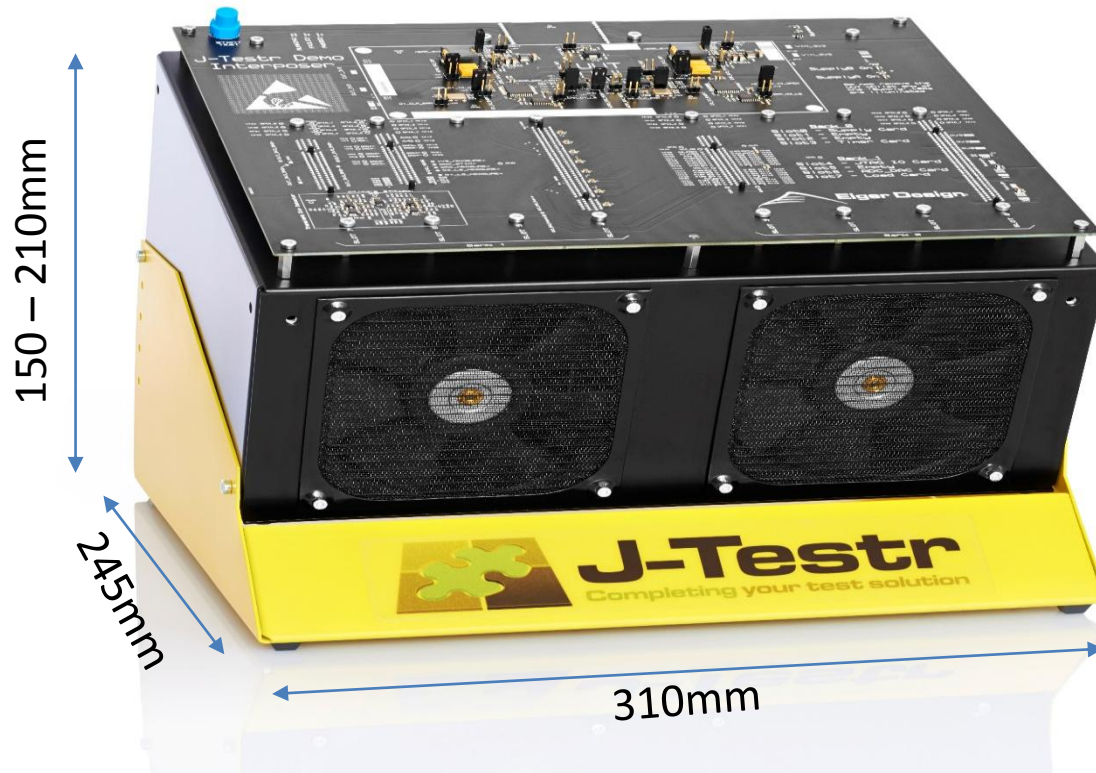


# J-Testr By Eiger Design

# Solution

- Very compact mechanical solution
- Easily reconfigurable/customisable
  - Simple to remove interposer (personality card)
- Simple and cheap Interconnection between test elements and UUT
  - Limited and in some cases NO cabling required
- Quick and Easy Interchangeable test elements (peripherals cards)
  - Easily expandable
- Easy to design special custom test elements (peripherals cards)
  - Open hardware peripheral front end with development board
- Integrated flexible power system
- Integrated cooling and advanced UUT power safety considerations
  - Protects untested UUT and equipment from power faults (rail shorts, OV conditions)
  - Maintains test environment
- Single simple test software
  - One language to learn
  - Faster Development
  - Lower costs
  - NO IPC required
- Provide a common test environment – Even for non JTAG UUTs!!!!
  - Maximise the JTAG Boundary tool investment
  - Common test platform
- Fast and simple memory mapped interface
  - Compared to IO bit bashing communications (SPI, I2C, etc) over JTAG
  - Instantly familiar to any engineer with Microprocessor/Microcontroller experience





# UUT Mounting Options



- Direct Mounting to Interposer
  - If UUT connections and size allows
  - Cheapest/fastest option
- UUT mounted to the UUT attachment plate
  - Connected via short cables from interposer
  - UUT mounting plate is a very simple four sided sheet metal design
    - Easy and cheaply customisable for the UUT
    - Simple UUT mounting can be done drilling standard blank UUT attachment plate
    - Low Cost
  - Attachment plate height (distance from interposer card)
- Bed of Nails (J-Testr Integrated to 'Bed of Nails' rig)
  - Higher volume testing
  - Easy of user connection

# **J-Testr**

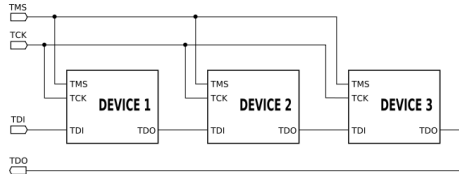
## **Making Development Easier**

## Breakout Cards



- Every peripheral card comes with a breakout card to allow the user to get up and running immediately without a Interposer.
  - Access to all the cards features
  - Easily fitted in minutes
  - Speeds learning and development times

# Remove Software Overhead

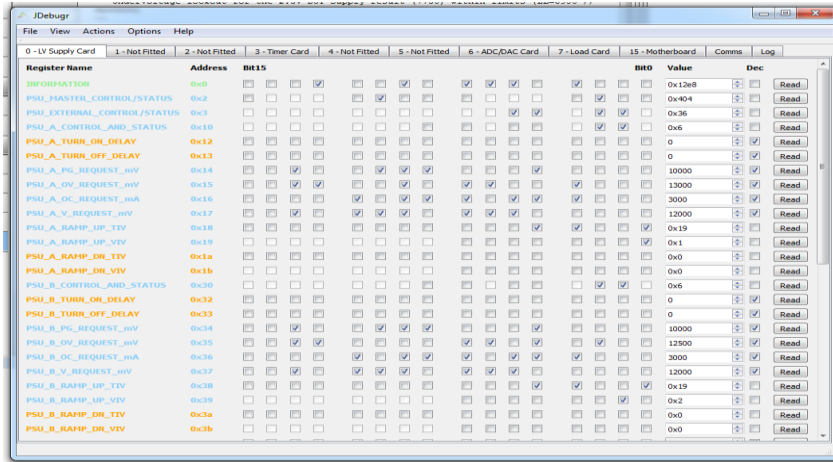


- Marvin "ATEasy"
- Native Python
- Native C++ <requires Ethernet option> (in development)
- All Driver are open Source!!!!

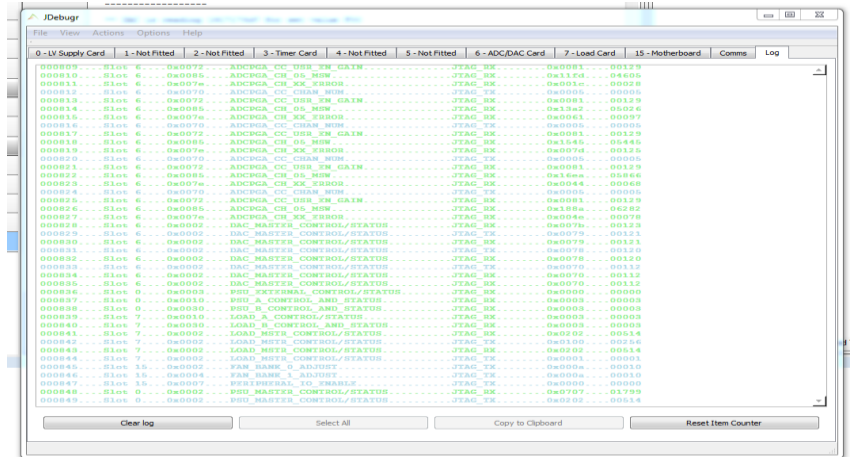
# Improve Diagnostics

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*There's always a Logic Solution!*



Register Name	Address	Bit15	Bit0	Value	Dec
0 - LV Supply Card	0x128			0x128	Read
1 - Not Fitted	0x129			0x129	Read
2 - Not Fitted	0x12A			0x12A	Read
3 - Timer Card	0x12B			0x12B	Read
4 - Not Fitted	0x12C			0x12C	Read
5 - Not Fitted	0x12D			0x12D	Read
6 - ADC/DAC Card	0x12E			0x12E	Read
7 - Load Card	0x12F			0x12F	Read
15 - Motherboard	0x130			0x130	Read
Comms	0x131			0x131	Read
Log	0x132			0x132	Read
Register Name	Address	Bit15	Bit0	Value	Dec
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Card	Address	Bit	Value	Description
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1 - Not Fitted	0x129	0	0	Not Fitted
2 - Not Fitted	0x12A	0	0	Not Fitted
3 - Timer Card	0x12B	0	0	Timer Card
4 - Not Fitted	0x12C	0	0	Not Fitted
5 - Not Fitted	0x12D	0	0	Not Fitted
6 - ADC/DAC Card	0x12E	0	0	ADC/DAC Card
7 - Load Card	0x12F	0	0	Load Card
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Comms	0x131	0	0	Comms
Log	0x132	0	0	Log
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3 - Timer Card	0x12B	0	0	Timer Card
4 - Not Fitted	0x12C	0	0	Not Fitted
5 - Not Fitted	0x12D	0	0	Not Fitted
6 - ADC/DAC Card	0x12E	0	0	ADC/DAC Card
7 - Load Card	0x12F	0	0	Load Card
15 - Motherboard	0x130	0	0	Motherboard
Comms	0x131	0	0	Comms
Log	0x132	0	0	Log

- Software let you see inside each peripheral card
  - See what has been Read and Written
  - Read and Write registers directly
- Activity Log
  - See the sequential activity
- Debug like a microcontroller!

**LSAFE**  
TECHNOLOGY



# Key Benefits

- **Complete** 'All-in-One' Test solution.
- Control via **JTAG** or **Ethernet** interfaces, with native JTAG controllable IO peripherals available.
- Super flexible, customizable, 'Bed of Nails' compatible.
- Fully **integrated** system power and thermal management.
- Advanced power up safety features (protects UUT).
- Very **easy** reconfiguration, within minutes (for re-use on multiple projects).
- One software environment to control both the 'UUT' and the 'Test Stimulus' when using a JTAG environment.
- Easy-to-use and **fast** programming .
- Software language independent (works with all common test software systems).
- Simple/Low-cost personalization card ('Interposer') easily and quickly designed.
- Custom stimulation peripherals possible with 'open hardware' interface circuitry.
- Highly compact, portable, and easy to store solution.

***Whether you think you can, or you think you can't – you're right.  
(Henry Ford )***

